## **Equipments for Physics Laboratory**

## **Specifications**

Notes: Product pictures are only for reference, CEIEC may update them due to technical reasons.

ІТЕМ:	CCD YOUNGG'S MODULUS MEASURING		
	INSTRUMENT		
PART NUBMI			
BASIC FUNC	TION:		
load, which is applied held fixe image-form display the way.	ation of deformation of a wire under h is parallel to the axis of the wire and to one end while the opposite end is ed. A microscope and CCD ming system is equipped to clearly e result and you can observe in an easy		
Stainless S		90 cm in length, 0.25 mm in diameter	
Molybdeni	um Wire	90 cm in length, 0.12 mm in diameter	
Upright Co	olumn	About 100 cm in height	
Reading M	ficroscope	Measuring range: 3 mm, min. graduate: 0.05 mm,14×	
CCD Video	o Camera	Effective pixel 752(H) ×582(V)	
Video Mor	nitor	Black and white, 35 cm, input impedance 75 $\Omega$	
Operating '	Temperature	.5 °C ~ 40 °C	
Ambient H	Humidity	10 ~ 80 %	
Total Mag	nification	54×	

<5%

Relative Uncertainty of Measurement

ITEM:	MEASURING INSTRUMENT FOR YOUNG'S MODULUS OF ELASTICITY WITH HALL POSITION	
	SENSOR	
PART NUMBER:	0201000002	
BASIC FUNCTION	N:	
Application of Hal	l position sensor to the traditional	
bending method of	measuring the Young's modulus of	
elasticity can make t	he educational contents richer and the	
experimental data m	ore stable and reliable. The deviation	3.
percentage between	n the measuring value and the	OF
commonly recognize	ed value is less than 3%.	
SPECIFICATIONS	: (As per one set)	
Measurement a	accuracy of reading	94
Sensitivity of Ha	all position sensor:	250 mV/mm.
Microscope:		0.01 mm,

ITEM: PART NUMBER:	EXPERIMENTAL INSTRUMENT FOR SHEAR MODULUS & MOMENT OF INERTIA 0201000101	
BASIC FUNCTION		
merits as follows: Claw disk at the designed. The r around the same perpendicular sta swing stably and The oscillation accuracy by Hall with magnetic ste period of ever periodicity for m measured with his The instrument c inertia about diffe	bottom end of wire has been well ring-shape rigid body can swing axis either in horizontal state or in the and the torsion pendulum can reliably.  period is measured with high a switch and intelligent time meter rel. Experimenters can look into the ry time and determine optimal reasurement. And the period can be gen accuracy.  an be used to measure moment of the rent axis of rigid body (ring). It can not the rent axis of rigid body (ring). It can not the rent axis of rigid body (ring).	SI S
DC source		5V
Digital timer	107	1 set
Max timing nun	nber	80
Digital timer me	easurement	250s

ITEM:	NEW-TYPE EXPERIMENTAL INSTRUMENT OF SINGLE PENDULUM	
PART NUMBER:	0201000200	
BASIC FUNCTION:		
sensor to measure pendulum accurat acceleration more study the influence	e oscillation period of single ely, thus to measure gravity accurately. It can be used to be of non-linear effect when endergoes big angle oscillation.	COS.
SPECIFICATIONS: (	As per one set)	
HTM electrical to with precision of 0	imer can time automatically .001 s.	JIRIN
Mirror and scale length of single	method is used to measure pendulum.	T & FILE

ITEM:	EXPERIMENTAL INSTRUMENT FOR STANDING WAVE ON THE STRING	
PART NUMBER:	0201000300	
BASIC FUNCTION	N:	
The instrumen	t can be used to observe the	
standing wave	forming on a string and get the	- 57
relationships or	n wavelength of standing wave,	
tension, vibran	t frequency, and line density of	2
string. It uses S	Single Chip Computer to control	OF
vibrant frequen	cy, which is digitally displayed.	
SPECIFICATIONS	S: (As per one set)	
Frequency adju	stable range:	0-200 Hz (continuously adjustable).
Frequency ste	p:	0.01 Hz.

ITEM:	NEW-TYPE EXPERIMENTAL INSTRUMENT OF JOLY BALANCE	- 1
PART NUMBER:	0201000400	
BASIC FUNCTIO	ON:	
measure the p and elastic co learn the chara switch, and r balance.	t can be used to verify Hooke's Law, period of simple harmonic oscillation pefficient of spring, help students to acter and utilization of integrated Hall measure the tiny tension with Joly IS: (As per one set)	
Range of Joly	balance:	0-551 mm,
Reading precis	ion:	0.02 mm,
Precision of a	millisecond meter:	0.001 s.
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LEEN.	ME ACTIDING INCODINGENT	
ITEM:	MEASURING INSTRUMENT	
	FOR LIQUID SURFACE	
DA DE MUMBED	TENSION COEFFICIENT	
PART NUMBER:	0201000500	Page 1
BASIC FUNCTION		N/
	t uses sensor to measure the	
	at the interface between liquid	
	the measuring results displayed	NAMERIAMEN
	meter. This instrument has the	-Br
	all measuring error and fine	0:
repeatability.	-i-4 C	R
	esistance force-sensitive sensor:	
SPECIFICATIONS		
Force measurin	g range:	0-0.098 N
Sensitivity:		About 3.00 V/N
CHIMAR	ALIONAL INSTITUTION OF THE STREET	

ITEM:	SYNTHESIS EXPERIMENTAL INSTRUMENT FOR MEASURING SOUND	
	VELOCITY	1
PART NUMBER:	0201000600	
BASIC FUNCTION:		
_	is multifunctional synthesis ment. It can be used to measure trately. It can observe not only the	
_	nding wave and resonance interface,	2.
but also the pheno	omenon of double-slit interference	
and single slit diffra	action. It can also form wave nodal	
diagram, if attached	to reflector board.	
SPECIFICATIONS: (A	As per one set)	OTAL
Sine wave signal ge	nerator: range of frequency:	38-42 KHz,
Display resolution o	of frequency:	0.001 KHz,
Digital display vern	ier caliper:	Measuring range: 0-200 mm
Precision:		0.01 mm,
Supersonic generato	or is fixed.	
Supersonic receiver	can rotate around fixed axis.	
Rotating angle:		-90°-90°
Rotating angle div	vision value:	1°.

ITEM:	MEASURING INSTRUMENT FOR LIQUID VISCOSITY COEFFICIENT BY THE METHOD OF
	0201000700
BASIC FUNCTION:	·
The instrument has	two ways of timing: one is
timing manually, the	e other is timing with laser
photoelectric sensor.	It can be used to measure
liquid coefficient of	viscosity and help students
to learn laser alignm	nent and to time with laser
photoelectric sensor.	
SPECIFICATIONS: (As	per one set)
Precision of tim	ing meter with laser
photo-electric sensor	:
Measuring error	of liquid coefficient of
viscosity:	

ITEM:	FORCED VIBRATION AND RESONANCE
	EXPERIMENTAL APPARATU
	(COMPUTER ACQUISITION)
PART NUMBER:	0201000800
BASIC FUNCTION:	
Forced vibration and res	onance are often used in engineering and scien
research. For example, in	fields of architecture and mechanical engineering
resonance is unfavorable a	and often needs to be avoided to ensure the quality
construction. However, in s	some petrochemical processing enterprises, principle
resonance is frequently us	sed to detect fluid density and fluid level. Therefo
- ·	nance are important laws of physics, and are getti
more attention in physics a	
1 ,	ning fork vibration system as the study object, and
	force of excitation coil as the excitation force, and
_	thip as the amplitude monitoring sensor, to measure
·	ibration amplitude and the frequency of the driving
•	n additional PC acquisition and analysis system, and
	ne resonance curve, and measure the mass of weight
b linear fitting method.	,
The apparatus can be used:	for following experiments:
1.Study the tuning vibrat	ing system in relation of amplitude and forced
frequency under the action	n of external periodic force, measure and draw the
-	ng system and find out the resonance frequency and
vibration acutance of vib	prating system, and then through the computer
automatically analyze the	curve based on the real time measured curve by
computer. Interface softwa	re can also be used to automatically collect data of
curve and to analyze the ha	
2.Measure the relationship	between the vibration of tuning fork and mass
symmetric double arms and	I find out the relation formula of tuning fork resonan
-	nass attached on certain position on the double arms
tuning fork.	
3.Measure mass of a pair	of mass blocks attached on the fixed position on
•	suring the resonance frequency, and automatically
	ction software. The apparatus has obvious physics
-	experimental data and is applicable to fundamental
-	gn and research experiment as well as lecture
experiment.	· ·

SPECIFICATIONS: (As per one set)

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ITEM:	COLLISION	LABORATORY	7	
	APPARATUS	LADORATORI		
	0201000900			
BASIC FUNCTION:	5201000700			1
Collision between objects is a ur	niversal nhenomeno	on in nature Single	2	
pendulum motion and horizontal thro	*	_		
Conservation of energy and cons				
concepts in mechanics. This collision		=		
collision occurring between two bal	, 11	•		
ball before collision and horizontal th				
with a view of solving the actual pro		_		
of mechanics laws acquired and find		•		
on the basis of difference value				
experimental result, so as to heighte				
solving problems. The apparatus has			4	
1. Can eliminate the parallax for the	=	=	า	
strength aluminum alloy, on which				- 2
slider.	15 11 5011	• pame was that on	_	
2. Can reduce the work to be done by	the bumped ball for	· overcoming the drag	3	
friction after being collided due to a	=		C	
conic fat head on its upper end, with				
ball can stay at stably with mass center				
of magnetic feld., the will be reduced	_	215		
3. Good repeatability of collision		t the hitch point of	f	,
pendulum ball and the mass center of				
by electromagnet and that of the	-	=		
apparatus is suitable for fundamen				
technical secondary school, and als	o for lecture experin	nent to be carried out	t	
in classroom.				
SPECIFICATIONS: (As per one se	t)			
Adjustable rack with electromagnet o	on it:			the rod i
Pendulum ball:				steel, 2.
The bumped ball:				Two pie
0,				1.8cm
Guide rail:				high str
				35cm lo
Ball carriage:				the upp
-				4mm, w
Target box:				30cm lo

Standing post:

45cm long, the cycloid can be changed in its length.

TOTAL C	MA CHERTS PARTY	<u> </u>			
ITEM:	MAGNETIC DAMPING				
	AND COEFFICIENT OF				
	KINETIC FRICTION				
	TESTING LABORATORY	Y			
	APPARATUS				
PART NUMBER:	0201001000				
BASIC FUNCTION:					
Magnetic damping is an	important conception of				
electromagnetism and widely ap	oplying on every physics feld,	1,	,	,	,
but it is seldom to directly b	be measured. With advanced	d			
integrated Hall sensor (hereina	after Hall switch for short),	),			
magnetic damping and coefficient	ent of kinetic friction testing	g	1	,	
laboratory apparatus is capable of	f measuring downslide velocity	у			
of magnetic slider on a no fe	erromagnetic good conductor	r			
inclined plane, and meanwhile f	finding out magnetic damping	g	;		
and coefficient of kinetic frictio	on after data processing. With	h			
Hall switch, the apparatus also c	can capable of measuring time	e	:	:	
and converting the nonlinear equ	ation into linear one by means	ıs	s		
of a clever data processing me	thod. This is a comprehensive	e	;		
physics experiment, with which	_			A 0	A 0
trained.			(8)		
The apparatus has following adva	intages:	<	W.		
1. Reliable design and easy angle	adjustment of the device;		,	1	<i>y</i>
2. Good repeatability and consist	tency of experimental data and	d			
less experimental error;					
3. Intellectualized timer can save	e the timing data for 10 times	es			
for looking up.					
The apparatus, with such fe	eatures as obvious physical	al			
phenomenon, reliable experimen					
application is very suitable for fu					
design study experiment and also	/				
SPECIFICATIONS: (As per on					
Adjustable angle range of inclined			0°~45	0°~45°	0°~45°
Length of inclined guide rail:				440mm	
Adjustable support:				630mm	
Intellectualized timer:					Timing frequency (memory):
intenectuanzed timer.					
					Timing range: 0.000-9.999s
	_		Timin	Timing resolution	Timing resolution: 0.001s

18mm in diameter, 6mm in thickness and 11.07mg of mass.

Magnetic slider:

ITEM:	AIR SPECIFIC HEAT CAPACIT RATIO MEASURING APPARATUS	
	(AIR ADIABATIC EXPONEN	T
	MEASURING APPARATUS)	_
PART NUMBER:	0201010002	4
BASIC FUNCTION:		_
• •	ratio measurement (i.e. air adiabatic expone	
	e important teaching experiments of comme	
	ded into the syllabus of physics experiment	
=	der to cooperate with universities and colleges	
	eaching appliances, improve the experiment	
	r company have jointly developed this ne	
-	t capacity ratio measuring apparatus. Air specif	
	ement is introduced in most common physi	~ <b>&gt;</b>
	Commonly they use U-shaped mercury gauge	
	neasure the pressure of air, and use mercu	
	perature. Because the pressure measurement h	
-	with mercury thermometer, measuring result	
•	s high. Air specific heat capacity ratio measuring	
	tion of experimental instrument based on t	
	itus. It uses silicon pressure sensor to measu	
_	s integrated temperature sensor to measu	E-translate.
=	t of air pressure and temperature is accurate an	
	d air specific heat capacity ratio is within 3	
• •	ue. Meanwhile, students can learn the princip	
	anced silicon pressure sensor and semiconduct	
	r, which greatly enriched the teaching conten	
	ratio measuring apparatus is equipped with	
	power supply and sampling resistance, so it	18
	attery and resistance box outside.	
The apparatus can be used to		10
	r specific heat capacity at constant pressure	10
specific heat capacity at constant volume		
2. Observing air state changing during thermodynamic process and its basic		
principle		a
3. Learning the principle and method of accurately measuring air pressure and		uu
temperature with sensor	w one cot)	-
SPECIFICATIONS: (As pe	i one set)	2. 2 and half digital valturator for many
Digital voltmeter:		2 3-and-half digital voltmeter for measurement
		pressure, 4-and-half voltmeter for measurement
		temperature

is

pressure, sensitivity 20mV/KPa

range

0-10KPa larger than environment air

Silicon pressure sensor:

ntegrated temperature sensor:	sensitivity 1uA/°C
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ITEM:	MEASURING INSTRUMENT	
	FOR SPECIFIC HEAT OF	
	METAL WITH COOLING	
	METHOD	
PART NUMBER:	0201010100	4.
BASIC FUNCTION:		*
The instrume	nt uses the amplifier of high	
sensibility, hig	h precision and low drift and the	
three-and-half	bit digital voltmeter to construct a	
second instru	ment with Copper-Constantan	
thermocouple	as a sensor. It has the feature of	
fine repeatability and small error. The deviation		
percentage between the measured specific heat		
of metal at 100	$^{\circ}\mathbb{C}$ and the commonly recognized	
value is less than 5%.		
SPECIFICATIONS: (As per one set)		
Resolution of	digital voltmeter:	0.01 mV,
Measuring range:		20 mV.

ITEM:	MEASURING INSTRUMENT	
	FOR LIQUID SPECIFIC HEAT	
	OF VAPORIZATION	
PART NUMBER:	0201010200	
BASIC FUNCTION		Ā
This meter make	es improvement to the heating up and	
gas transporting	g units of the traditional ones for	
liquid specific l	neat of vaporization. A temperature	
control circuit i	is added to the heating up electric	The last of the la
stove; polystyrei	ne expanded plastic is filled between	
the shell and i	nternal cup of the calorimeter for	2
thermal insulation	on; and integrated temperature sensor	COL
is used to measu	re temperature.	
SPECIFICATIONS	: (As per one set)	
Resolution of a	ligital voltmeter:	0.01 mV
Measuring rang	ge:	20 mV.
CHIMA P.	NCATIONAL INSTRUMENTAL INSTRUME	

ITEM:	MEASURING INSTRUMENT FOR	R
	SOLID LINEAR THERMAI	
	EXPANSION COEFFICIENT	
PART NUMBER: 0201010500		
BASIC FUNC	CTION:	
The instrument uses Single Chip Computer and temperature sensor to control temperature. It can be		
used to observe solid character of thermal expansion		
and contraction, and measure linear thermal expansion		
coefficient of metal accurately.		
SPECIFICATIONS: (As per one set)		<u> </u>
Temperature reading accuracy:		0.1 ℃
Range of temperature controlling:		Room temperature—80 °C
Temperature non-uniformity in stove in equilibrium		<0.3 °C,
Precision of elongation:		0.001 mm
Largest measuring range:		0-1 mm.

ITEM:	EXPERIMENTAL CONSTANT TEMPERATURE INSTRUMENT FOR TEMPERATURE	
	CONTROLLING WITH	2
	TEMPERATURE SENSOR	
PART NUMBER:	0201010600	1
BASIC FUNCTION	N:	
The instrument is high-precision digital constant temperature instrument. It can be used to measure the features of all sorts of temperature sensors, and the relation between resistance and temperature of all kinds of material, and also can be used as constant temperature instrument for some experiments.  SPECIFICATIONS: (As per one set)		
Range of tempe	rature controlling:;	Room temperature—80 ℃
Precision of temperature controlling:		±0.1°C,
Measuring ran sensor:	ge of DS18B20 temperature	-55 ℃——+125 ℃,
Measuring res	olution:	0.0625 ℃.

ITEM:	EXPERIMENTAL INSTRUMENT FOR TEMPERATURE SENSOR TEST AND TEMPERATURE CONTROL BY SEMICONDUCTOR REFRIGERATION	
PART NUMBER:	0201010602	
BASIC FUNCTION	<b>\:</b>	
The knowledg	e about performance and test of	-
temperature sensor	is an essential content of college	
physics experiment	t. However, most experimental	
instrument can only	be used above ambient temperature.	
FD-TM experimenta	l instrument for temperature sensor	
test and temperature control by semiconductor		014
refrigeration can be used for experiments below ambient		
temperature because it is provided with function of		
semiconductor refrigeration. The instrument is mainly		. 7
used to test the performance of temperature sensor		
AD590 (and other	temperature sensor according to	
	can acquaint experimenter with the	
performance of semi-	conductor refrigerator stack.	
SPECIFICATIONS: (As per one set)		
Temperature range of heating:		ambient temperature−120 °C;
Temperature range of cooling:		45 °C below ambient temperature — ambien
		temperature (about -10 °C $=$ 15 °C);
Precision of contro	olling temperature:	0.1 °C;
Precision of mea	asuring temperature:	± 3%.

ITEM:	THERMAL	CONDUCTIVITY
	MEASURING AP	PPARATUS
PART NUMBER:	0201010702	

## **BASIC FUNCTION:**

Thermal conductivity is a physics quantity representing the heat conducting characteristic of a matter, but change of material structure and different content of impurity have obvious influence on it, therefore, the thermal conductivity of material often needs to be measured on particular requires. Two of steady state method and dynamic method are available for measuring thermal conductivity. By steady state method, the specimen should be preheated in result to make heat conduct from high temperature to the low inside the specimen due to reason of temperature difference, thus the temperature of each point insider the specimen vary with the speeds of heating and conducting, and then give proper control to experiment conditions and parameters to make the process of heating and conducting reach to a balanced state, with which the specimen will have a stable temperature distributed inside. Based on it, the thermal conductivity can be found out. This apparatus is designed adopting the steady state method for measuring the poor conductor (such as rubber), with which we can learn the experimental technique of utilizing the rate of heat release of object to find out conducting speed. The apparatus, with steady state method, is used for measuring the poor conductor. It is the second generation, the heating disc of which is changed to of self-adapting temperature control by monolithic processor with 0.1°C of reading resolution. The heat emission disc is designed with integrated sensor for temperature measurement, the reading resolution of which is 0.1°C. With firm structure, easy measurement and control, the apparatus has been widely applied on heat experiment of general physics in universities and colleges.

The apparatus is capable of doing the following experiments:

- 1. Measure the thermal conductivity of poor conductor. Rubber specimen is attached with the apparatus for teaching purpose.
- 2. Learn the experimental technique of utilizing the rate of heat release of object to find out conducting speed.
- 3. Learn usage of high accuracy integrated temperature sensor.

## SPECIFICATIONS: (As per one set)

Working temperature:	0°C~100°C	
Thermostatic control range:	ambient temperature-80°C	
Display resolution:	0.1 ℃	
Uncertainty of measured thermal conductivity:	less than 6℃	



Measure the specimen of poor conductor	such as rubber
weasure the specimen of poor conductor	such as rubber

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ITEM:	MEASURING INSTR FOR SOLID M REFRACTION INDE	MEDIUM	
PART NUMBER:	0201020000		eq.
BASIC FUNCTION:			- <del>-</del>
The instrument can be u	used to observe and an	nalyze the	4 N 2 7 7
phenomenon of optical	polarization. It can me	easure the	
refractive index of solic	d material, which is tr	ansparent	
based on law of Brev	wster. By measuring	reflection	
coefficient of polarized light, experimenter can get the		n get the	A - 23300
diffractive index of solid material.			OPI.
SPECIFICATIONS: (As per one set)			
Light source: wavelength of semiconductor			650 nm, power 1.5-2.0 mW
Outer dial can be rotated for 360°.			DIA
Division value:			10
Digital optical powereceiver:	er meter with photo-	electricity	, dip
Its range has two steps:			0.2 mW and 2 mW.

Measurement Error

THREAD & SINGLE SLIT DIFFRACTION  PART NUMBER: 0201020200  BASIC FUNCTION:  The instrument can be used to observe phenomenon of optical diffraction and measure the diameter of single thread and width of single slit by using the method of	
PART NUMBER: 0201020200  BASIC FUNCTION:  The instrument can be used to observe phenomenon of optical diffraction and measure the diameter of single	
BASIC FUNCTION:  The instrument can be used to observe phenomenon of optical diffraction and measure the diameter of single	
The instrument can be used to observe phenomenon of optical diffraction and measure the diameter of single	
optical diffraction and measure the diameter of single	
thread and width of single slit by using the method of	
optical diffraction	
SPECIFICATIONS: (As per one set)	
Single thread single slit mini pore diffraction, etc	
Wavelength of semiconductor laser: 650 nm	
Length of optical bench: From 500 mm to 1000 mm	
Division value: 1 mm.	
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ITEM:	AUTOMATIC DIFFRACTION INTENSITY RECORD SYSTEM	
PART NUMBER:	0201020300	
BASIC FUNCTION	:	
single slit, mu current, which Powerful softwar	transforms diffraction pattern of alti-slit, multi-hole, etc., into is then displayed by monitor. The is used to analysis the result.	
SPECIFICATIONS	: (AS PER ONE SET)	P
Wavelength Ra	nge	200mm
Measurement A	Accuracy	±0.01mm
He-Ne Laser		632.8nm, over 1.5mW
Single Slit		Continuously adjustable from 0 to 2mm
Diffraction Boa	ard Group	Slit width: 0.03mm, interval:0.06mm
Grating Scale		Grating Pitch: 0.02mm, Accuracy: ±0.01mm

ITEM:	EXPERIMENTAL INSTRUMENT FOR OPTICAL ROTATION OF POLARIZED LIGHT	
PART NUMBER:	0201020400	
BASIC FUNCTION	V:	
Optical rotation effect	et has a lot of applications in scientific	4 (
research and technique	ue detection department. For example,	
pharmaceutical in	ndustry, medicine examination	
department and con	nmodity inspection department often	
measure the concent	tration of drug and commodity with	3.
the method of optical	l rotation. The instrument can be used	OF
for many experimen	ts of polarized light: optical rotation	
effect, light polariza	tion experiment, and verification of	
Malus law and so on		
SPECIFICATIONS	: (As per one set)	
Wavelength of sen	niconductor laser:	650 nm
Working voltage		3V <sub>2</sub>

	T	
ITEM:	CHROMA	
	EXPERIMENTAL	
	DEVICE	
PART NUMBER:	0201020500	
BASIC FUNCTION:		
Automatic detection	of dominant wavelength of	
the sample under	experiment, as well as 3	
stimulus values of co	olor.	
2colour metric	modes available:	
transmission-type, a	nd reflection-type.	
Measurement of any	light source.	3.
SPECIFICATIONS: (A	AS PER ONE SET)	COL
Wavelength Range	2	200-800(380-780nm for chroma experiment)
Wavelength Accur	acy	≤±0.4 nm
Wavelength Repea	atability	≤0.2 nm
Relative Aperture		D/F = 1/7
Focal Length of C	follimation Mirror	302.5 mm
Stray Light		≤10 <sup>-3</sup>
Grating		1200 L/mm, blazed wavelength at 250nm
Transmittance Acc	curacy	≤±1%
Noise		≤±0.5%
Integral Sphere		$\Phi$ =150 mm

	T	T
ITEM:	BLACKBODY RADIATION	
	MEASUREMENT	
	INSTALLATION	
PART NUMBER:	0201020600	
BASIC FUNCTIO	ON:	
This device u	uses grating monochromator and	
computer tech	nology to measure radiant energy	
of light source	e and clearly display blackbody's	
radiant energy	curve on the terminal. Dual data	
acquisition fo	ormat makes laboratory report	
writing easier	r for students. Also used for	28.
verifying of P	lank's blackbody radiant law and	OF
Stefan-Boltzm	ann law.	
SPECIFICATION	IS: (AS PER ONE SET)	
Wavelength I	Range	800—2500nm
Wavelength A	Accuracy	≤±4 nm
Wavelength I	Repeatability	≤2 nm
Relative Ape	rture	D/F = 1/7
Focal Length	of Collimation Mirror	302 mm
Grating		300L/mm
Dimension		360×300×160mm

FOURIER TRANSFORM	
SPECTROMETER	
0201020800	
020102000	
pectrometer with external	
asuring range in the visible	
0-800 nm to capture the	
alize the optics of Fourier	
nd free students from math	
	28.
s per one set)	OF
	25000-12500 cm-1 (400 -800 nm)
	15.6cm-1(1 nm @800nm)
acy	1nm
LINE'TP	
)	asuring range in the visible 0-800 nm to capture the alize the optics of Fourier d free students from math

ITEM:	PLANK'S CONSTANT	
	EXPERIMENT UNIT	
PART NUMBER:	0201020900	
BASIC FUNC	CTION:	11
electrons stimu current, to e Planck's cons fundamental u light and to f photoelectric e	ent, using the photoelectric effect, where alated by incoming light create an electric experimentally determine the value of stant (h), allows students to get a enderstanding of the quantum character of familiar with experiment skill related to effect.  (S: (As per one set)	OR.
Wavelength F	Range	200-800nm
Slit Width		0.3mm
Wavelength A	Accuracy	±3nm
Wavelength F	Repeatability	±1nm
PMT		GD31A <sub>Q</sub>
DC regulated p	power supply	±1.8V digital
Light Source		12V, 75W bromine tungsten lamp

ITEM:	HENE LACED MODE ANALYZED	
	HENE LASER MODE ANALYZER	
PART NUMBER:	0201021000	
BASIC FUNCTION	<b>I:</b>	
With this device,	, student may	
Be familiar with principle and operation of confocal		
spherical scanning interferometer		
Observe longitudinal and transverse modes distribution.		E E E
Observe of sever	ral of modes of different lasers.	William .
Determine mode	structure by calculating modes spacing	
of the laser		23.
SPECIFICATIONS	: (As per one set)	
He-Ne Laser		
Cavity Length		246mm
Wavelength Ac	ecuracy	1nm
Curvature of R	esonator	1m-∞
Center Waveler	ngth	632.8nm
Confocal Spheric	cal Laser Resonator	
Cavity Length		20mm
Curvature of C	oncave Mirror	20mm
Reflectivity of	Concave Mirror	99%
Fine Constant		>200
Free Spectral Ra	nge	4GHz
Interval Error	107	≤20MHz

	T	
ITEM:	HENE LASER EXPERIMENT	
	SERIES	
PART NUMBE:	0201021001	
BASIC FUNCTIO	ON:	
Adjustment	of laser with variable front	
cavity		
Measurement of light spots distribution and		****
calculation o	f angle of divergence.	
Observation	of transverse mode and	2 5
longitude mo	ode with a confocal spherical	
laser resonate	or.	2.
Measurement	t of fine constant of confocal	
spherical lase	er resonator.	
SPECIFICATION	NS: (As per one set)	
He-Ne Laser		a M
Curvature of	Resonator	1m ∞
Center Wave	length	632.8nm
Confocal Sphe	erical Laser Resonator	***
Cavity Lengt	h	20mm
Curvature of	Concave Mirror	20mm
Reflectivity	of Concave Mirror	99%
Fine Constan	t	>100
Free Spectral I	Range	4GHz

ITEM:	EXPERIMENT DEVICE FOR SEMICONDUCTOR LASER PUMPING	
PART NUMBRE:	0201021003	
BASIC FUNCTION	V:	
With this devi	ce, we get 532nm laser with a 808 nm	
semiconductor p	oump Nd: YVO4 laser which involve a lot of	
light path adju	stment, allowing students to acquire more	
familiarity on th	e principle practically.	
Many fundamen	tal parameters are measured with this device.	
SPECIFICATIONS	: (As per one set)	2.
808nm Semico	nductor Laser	≤500mW
Power Supply	for Laser	0~500mA
Nd: YVO 4 crys	tal	3×3×1mm
KTP		2×2×5mm
Output Mirror		φ6 R=50mm
Light power met	ter	2μW~200mW

when the light beam is passing through, wherefrom the propagation speed of sound wave in liquid can be measured accurately. The acousto-optic effect can be applied widely because the developing lase and ultrasonic techniques. Though ultrasonic grating experiment, the experimenter can get to know the experimental theory of optical effect to learn to use the optical effect to measure the sound velocity in liquid and the application method of the micrometer ocular.  Ultrasonic grating laboratory apparatus manufactured by our company	
BASIC FUNCTION:  The light wave is diffracted by the ultrasonic wave when it propagates in liquid medium, which is called the optical diffraction caused by ultrasonic sound (also called acousto-optic effect). This phenomenon is the interactional result from light wave and sound wave in medium. The liquid density is modulated by the making the original liquid with even diaphaneity become the "ultrasonic grating" of which refractive ratio changes periodically. The diffraction phenomenon is to be produced when the light beam is passing through, wherefrom the propagation speed of sound wave in liquid can be measured accurately. The acousto-optic effect can be applied widely because the developing lase and ultrasonic techniques. Though ultrasonic grating experiment, the experimenter can get to know the experimental theory of optical effect to learn to use the optical effect to measure the sound velocity in liquid and the application method of the micrometer ocular.  Ultrasonic grating laboratory apparatus manufactured by our company	
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and the application method of the micrometer ocular.  Ultrasonic grating laboratory apparatus manufactured by our company	
Ultrasonic grating laboratory apparatus manufactured by our company	
1 0 11 : 0 /	
has following features:	
1.Optical guideway is used to facilitate level and vertical adjustment	,
and the outdated bulky spectrometer platform is abandoned, so th	
apparatus is light to be moved.	
2.Mechanical adjustable slit arrangement is replaced with optical slit, s	
that the grating spectrograph is fine and obvious.	
3. The apparatus has a integrated structure and high accuracy, and tes	t
data is reliable.	
This Ultrasonic grating laboratory apparatus mainly consists of	f
mainframe (control box), sodium vapour lamp, optical guideway, liqui	d
tank, collimator and micrometer ocular.	
SPECIFICATIONS: (As per one set)	
Ultrasonic sound source:	resonance frequency is 10.000MH
	approximately; resolution is 0.001MHz.
Photolithographic slits:	slit is 0.04mm in width; slit is 6mm in length
Lens:	transmission aperture is φ 28mm; foca
	length is 157mm.
Liquid tank:	80mm in length; 40mm in width; 59mm is
	height
Micrometer eyepieces:	measured range within 0-8mm; resolution is
	0.01mm.
Optical guide rail:	1

resolution is 1mm.

		_
	UNIVERSAL	
	INTERFEROMETER OF	
	MICHELSON AND	D
	FEBRY-PEROT	
PART NUMBER:	0201021401	
BASIC FUNCTION:		
Demonstration of the	ne structure of Michelson	n
interferometer and Fe	ebry-Perot interferometer	
	rference fringes of equal	1
_	ckness fringes, white light	ıι
fringes.		
Determination of way	Determination of wavelength of laser	
Determination of	refractive index of	f
transparency slice and of air		
Observation of fine st	Observation of fine structure of spectra.	
SPECIFICATIONS: (As		
·	itter and Compensator	
Flamess of Deam Spir	itter and Compensator	
Min Division Value o	of Movable Mirror	$\exists$
Travel of micrometer	Travel of micrometer	
	, (	ړط
Barometer		X
Laser Output		
Wavelength Measure	ment Accuracy	

ITEM:	GRATING MONOCHROMATOR	
PART NUMBER   0201021601		B
BASIC FUN	CTION:	
A monochromator, frequently used as a part of spectrometer, is capable of producing a single spectral line from a broadband (multi-wavelength) source.  SPECIFICATIONS: (AS PER ONE SET)		
Wavelength Range		200 — 800nm
Focal Length		300nm
Wavelength Accuracy		≤0.4nm
Wavelength Repeatability		≤0.2nm
Slit		Continuously adjustable from 0 to 2mm

ITEM:	MODULARIZED	
	MULTIFUNCTIONAL GRATING	
	SPECTROMETER	
PART NUMBER:	0201021604	
BASIC FUNCTIO		4
Observe the	sodium double lines and spectrum of	
Mercury lamp.		
Calibrate the C	CCD Grating Spectrometer	
Measure the R	ydberg constant	
Measure isotop	e shift of Hydrogen and deuterium	
SPECIFICATION	S: (AS PER ONE SET)	3.
Wavelength F	Range	PMT: 200-660 nm
		CCD: 200-660 nm
Resolution		≤0.06 nm
Focal Length		500mm
Slit		Continuously adjustable from 0 to 2mm
Relative Ape	rture	D/F=1/7
Wavelength A	Accuracy	≤±0.4nm
Wavelength F	Repeatability	0.2nm
Stray Light		≤10-3
Dimension		560X380X230 mm
Weight		30Kg
S	ALIDUCATIONAL.	

ITEM:	MULTIFUNCTION OPTICAL	
IIEMI:		
	EXPERIMENTAL	
PART NUMBER:	INSTRUMENT 0201022100	
BASIC FUNCTION		
	basic optical physics experiments	
`	, 1	
_	ion Index measurement, Characters	
	rement and Single Thread & Single	
_	eriment) can be done on it. It has	
_	ecuracy, never rustiness, and being	R
capable of using it in		
SPECIFICATIONS	· · · · · · · · · · · · · · · · · · ·	
Optical bench length	:	50.0 cm
Division value:		1 mm.
Wavelength of sen	niconductor laser:	650 nm.
	inconductor laser.	

ITEM:	EXPERIMENTAL	
1112111.		
	INSTRUMENT OF LIQUID	
	CRYSTAL (LC)	
	ELECTRO-OPTIC EFFECT	
PART NUMBER:	0201022200	<u> </u>
BASIC FUNCTION	v:	
The instrument	can be used to measure the	
electro-optical cu	rve and the electro-optical response	
curve of LC sa	mple. It can help the students to	
understand the ba	sic principle of LC display and study	
other LC physical	characters.	3.
SPECIFICATIONS	: (As per one set)	COV
Semiconductor laser:		Wavelength 650.0 nm, power: 2 mW
Voltage of square wave:		0-10 V, continuously adjustable
Frequency: about;		500 Hz
Power meter of light:		Its range has two steps of 0.2 mW and 2 mW.
Length of optical bench:		50.0 cm.

ITEM: MEASURING INSTRUMEN FOR LENS FOCUS		
PART NUMBER:	0201022300	
BASIC FUNCTION:		
The meter can measure focus of concave lens or convex lens based on the theory of lens imaging, using high luminosity LED as light source.		
SPECIFICATIONS	S: (As per one set)	AMPS STORY
Length of optical be	nch:	From 500 mm to 1000 mm
Division value:		1 mm
Output power of light source:		DC 3 V/200 mA

TEM:	BIPRISM OPTICAL INTERFERENCE	CE
	LABORATORY APPARATUS	
PART NUMBER:	0201022400	
BASIC FUNCTION:	1	
In 1826, Fresnel, a Fre	ench scientist, used a biprism to divide way	ve
front of a beam of coh	erent light into two parts to form compone	ent
wave interference, with	n which the interference fringe spacing (	in
millimeter magnitude) v	was measured and in consequence to have the	he
light wavelength (in	nanometer magnitude) being found out. The	he
physics concepts and	experimental technique concerned with th	nis
experiment are valuable	e for teaching. This biprism embodies th	he
following advantages:		OF
1. Coherence and with	out damage your eyes due to a laser source	ce
greatly reduced in lig	ht intensity by a monochromatic source	of
semiconductor laser, w	hich is convenient to make the interference	ce T I I
fringe image in focus, a	and also easy to adjust the interference fring	ge
of sodium light.		
2. Able to stand wear and operating without rustiness due to the		he of
application of high stre	ngth and quality aluminum alloy to guide ra	ail
and turntable, design o	f dovetail groove structure and agility of the	he
turntable.		
3. Allowable to carry	out optics experiment in white light ar	nd
ventilating condition du	e to a black light-shield house equipped with	ı.
The apparatus is suital	ole for foundational physics experiment ar	nd
design and research in c	olleges and universities.	
The apparatus is capable of doing the following experiments:		
1. Observe the biprism optical interference phenomenon.		
2. Measure wave length of laser and that of yellow light of sodiun		m
lamp		
3. Observe the interference phenomenon of other light source.		
SPECIFICATIONS: (	As per one set)	
Guide rail:	<del></del>	80.0cm long; division value: 1mm; s
		5pieces, in which one with rotary actuator.
Slit with turntable:		the width of the slit is 0.03-0.04mm

range 0-8mm; division value: 0.01mm.

650.0nm; operating voltage: dc 3V

1) semiconductor laser, optical wave length:

Micrometer eyepiece and bracket:

Sodium lamp and power supply (optional)

Light source:

ITEM:	CURRENT ILLUMINATIO	N
	CHARACTERISTIC LABORATOR	$\mathbf{Y}$
	APPARATUS OF PHOTO SENSOR	
PART NUMBER:	0201022500	
BASIC FUNCTION:		
In optical experiment, a	a photo sensor is necessary for measuremen	ıts
such as the illuminance	ee of a position, luminous intensity of lig	ht
source, light distributio	n of diffraction and interference, optical fib	er
optics measuring, extin	ction position and intensity of polarized lig	ht
etc. The photo sensor is	s an element that is capable of converting t	ne
physics quantity of lig	ht intensity into electricity quantity. It is	an S.
important apparatus to	be applied on modern optical measurement	nt.
Therefore, the experim	nent of current illumination characteristic	of
photo sensor is one of	essential physical experiment in colleges as	nd
universities. The type	current illumination characteristic laborato	ry
apparatus of photo sens	sor is an improved one based on the type	A, -000 -1220
which embodies the foll	lowing advantages:	
1. Free adjustable in lu	minous intensity of light source by request	of O
experiment; selectable i	n dc power supply with different voltage for	it
is equipped with several	l sets of power supply. It is reliable and easy	ìn
adjustment.		
2. There four kinds pl	hoto sensors for selection: silicon photoce	11,
light-sensitive resistor,	light-sensitive diode and photistor etc. t	ne
	varied in experimental content and high	in
availability.		
	e of doing the following experiments:	
	nination characteristic of silicon photocell;	
2.Measure current ill	lumination characteristic of light-sensiti	ve
resistor;		
3. Measure current illun	nination characteristic of light-sensitive diod	2;
4. Measure current illun	nination characteristic of photistor	
SPECIFICATIONS: (A	As per one set)	
Light source (Osram lar	mp):	illuminance 0-300Lx.
Dc power supply:		±2V, ±4V, ±6V, ±8V, ±10V, ±12V, six gr
		output current: ≤0.3A adjustable power su
		$0-24V$ , output current $\leq 1A$
De dicital columnton		range 1.9999V; resolution 0.0001V; R
Dc digital voltmeter:		19.999V resolution 0.001V

0-200mV±0.1%; resolution 0.01mV

Scaled digital voltmeter:

ITEM:	MEASURING INSTRUMENT FOR HYSTERESIS LOOP AND	
	MAGNETIZATION CURVE OF	
	MAGNETIC MATERIAL	
PART NUMBER:	0201030000	
BASIC FUNCTION	<b>1:</b>	
The instrument	supplies three different kinds of	
magnetic mater	rial. It uses high precision digital	
TESLA meter	to directly measure magnetic	
induction intens	ity $B$ in the small inter space of the	
magnetic circuits, thus getting initial magnetization		3.
curve and magnetic hysteresis loop.		Or
SPECIFICATIONS: (As per one set)		
Digital TESLA meter:		LED display,
Range:		2.000 T;
Resolution:		0.1 mT;
Constant current source:		LED
Display Range	2:	0-600.0 mA (adjustable);
Total turns number of magnetizing coil:		N=2000.

ITEM:	NEW-TYPE MAGNETIC FIELD MEASURING INSTRUMENT WITH CIRCULAR COIL AND HELMHOLTZ COIL	,
PART NUMBER:		<b>(2) (4)</b>
BASIC FUNCTIO	N:	
Using this type integrated Hall sensor as detector and including a high sensitive digital-type milli-Tesla meter this instrument can be used to learn how to measure weak magnetic field, verify the superposition principle of magnetic field and measure the magnetic field distribution of HELMHOLTZ coil.  SPECIFICATIONS: (As per one set)		BBB BBB COR
· • • • • • • • • • • • • • • • • • • •		0-2.000 mT
Resolution:		0.001 mT;
Turns of coil:		500;
Measuring error of magnetic induction intensity:		<3%.

	T	
ITEM:	EXPERIMENTAL	
	INSTRUMENT FOR	
	MAGNETORESISTIVE EFFECT	
PART NUMBER:	0201030200	
BASIC FUNCTION	<b>\</b> :	
The instrument u	ises two kinds of sensors. It studies	
resistance magni	tude of InSb magnetic resistance	
sensor in different magnetic field intensity by using		15-W41
GaAs Hall sensor to measure magnetic induction		1111111
intensity. It can also be used to get the fitting formula		ACCOUNT OF THE PARTY OF THE PAR
of relation between resistance and magnetic induction		
intensity.		<b>3</b> .
SPECIFICATIONS: (As per one set)		OF
Range of working current:		0-500mA (continuously adjustable);
Measuring range of digital milli-Tesla meter:		0-0.5 T,
Resolution:		0.0001 T, Accuracy, 1%.

ITEM:	EXPERIMENTAL	
	INSTRUMENT FOR	
	MEASURING GEOMAGNETIC	
	FIELD WITH MAGNETIC	
	RESISTANCE SENSOR	
PART NUMBER:	0201030201	
BASIC FUNCTION	<b>1:</b>	
The instrument	uses new-type Perm alloy magnetic	
resistance senso	or to measure some important	
parameters of geomagnetic field (horizontal		
component, magnetic inclination). The magnetic		A TA ALA S
resistance sensor	has the merits of high sensitivity	160
(50V/T), fine resolution ( $10^{-7}$ - $10^{-8}$ T) and high stability.		
SPECIFICATIONS: (As per one set)		
HELMHOLTZ coils:		Turns number of single coil N= 500
Uncertainty of horizontal component of geomagnetic		<3%
field:		<3%
Uncertainty of magnetic inclination:		<3%
Radius:		10 cm

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ITEM:	MEASURING INSTRUMENT FOR CHARACTERS OF SOLAR CELL (SILICON PHOTOELECTRIC CELL)	
PART NUMBEI		
BASIC FUNCT		
	can measure volt-ampere character	2 2
	vith or without illumination. It can	
	pasic parameter of solar cell and	
measure the	relationship between short-circuit	23.
current/open-ci	rcuit voltage and relative light	
intensity. It car	also measure the basic character of	
silicon photoele	ectric cell.	
SPECIFICATIO	ONS: (As per one set)	ON
Light power:		40 W,
Range of ligh	nt power meter has two steps:	0.2 mW and 2 mW.
	nt power meter has two steps:	

ITEM:	EXPERIMENTAL INSTRUMENT	
	FOR HALL EFFECT	
PART NUMBER:	0201030400	
BASIC FUNCTION	N:	
experimental pr sensitivity of Ha	can be used to help student grasp the inciples of Hall Effect, measure the all element, and learn the method of nent (GaAs Hall sensor) to measure netic field.	
SPECIFICATIONS	: (As per one set)	ORX
Digital TESLA	meter:	Range 0-0.35 T
Division value:		0.0001 T
Electromagnet in	nter-space:	3 mm.
CHIMA	nter-space:	

ITEM:	MEASURING INSTRUMENT FOR PN	
	FUNCTION'S PHYSICS FEATURE	
	(MEASURING INSTRUMENT FOR	
	BOLTZMANN CONSTANT)	
PART NUMBER:	0201030500	
BASIC FUNCTIO	N:	TARREST .
The instrument	can be used to measure the physical feature	111111111
of PN junction	and Boltzmann constant and to help students	TO A THE TOTAL TOTAL AND THE PARTY OF THE PA
learn a new me	ethod for measuring weak current. It is also	2012
equipped with	thermostat and can be used to study the	The state of the s
relation of jun	ction voltage U <sub>be</sub> and temperature T, thus	
approximately	obtaining the bandwidth of silicon forbidden	R
band at 0 K.		
SPECIFICATION	S: (As per one set)	
Range of tempe	erature controlling:	Room temperature80 °C;
		Y

Precision of temperature controlling:

ITEM:	EXPERIMENTAL INSTRUMENT OF NON-LINEAR ELECTRICAL	
	CIRCUIT CHAOS	
PART NUMBER:	0201031101	
BASIC FUNCTION	N:	
The circuit boar	rd of the instrument is mainly composed	
of LC oscillate	or, RC phase shift circuit, non-linear	4
negative resista	ance element, etc. It can be used to	4 A 1 A 1 A 1 A 1 A 1 A 1 A 1 A 1 A 1 A
measure voltag	ge-ampere characteristics of non-linear	
resistance and	observe periodic bifurcation of sine	
wave, the phenomenon of chaos and period variation of		
phase diagram.		OF
SPECIFICATIONS	S: (As per one set)	
Range of digit	tal voltmeter:	0-20 V

Resolution:

ITEM:	FOURIER DECOMPOSITION	1
	AND SYNTHESIS INSTRUMENT	
PART NUMBE	R: 0201031400	
BASIC FUNCT	TION:	
The Instrun	nent is a teaching one for university students	
to study F	ourier analysis method. It can be used to	
accomplish	the experiment of Fourier decomposition and	
Fourier syn	thesis. It can help the students to grasp the	
physical m	eaning and measuring method of Fourier	
analysis.		
		2.
SPECIFICATION	ONS: (As per one set)	OF
Frequency of	of square wave:	1000 Hz Error ≤ 3%,
Amplitude:		0.4-1 V (continuously adjustable);
Frequency of	of triangular wave:	1000 Hz Error < 3%;
Amplitude	:	0.4-0.9 V (continuously adjustable).

ITEM:	EXPERIMENTAL	
	INSTRUMENT	OF
	RAMSAUER-TOWNSEND	
	EFFECT	
PART NUMBER:	0201100000	
BASIC FUNCTION	N:	

Experimenters can use the instrument to accomplish the following experimental content:

Learning the design principles of electron collision tube, grasping the collision rules between electron and atom and grasping the measuring method of atomic scattering cross section.

Measuring the relation between electron velocity and the scattering probability of low energy electron scattering among gas atom.

Calculating the effective elastic scattering cross section of gas atom;

Measuring the electron energy relevant to the minimum of the scattering probability or scattering cross section.

Verifying the Ramsauer-Townsend Effect, and explaining the effect with the theory of quantum mechanics.



Source voltage	0~5V
Accelerating voltage	0~15V
Compensate voltage	0~5V

ITEM:	FRANK-HERTZ EXPERIMENTAL	
-	INSTRUMENT	
PART NUMBER:	0201100101	
BASIC FUNCTION		
The instrument	is designed to help the students to	- X
understand the B	ohr quantum theory. The experiment can	BORRO O COCO
prove the quanti	zation of the internal energy of atom by	
using electron to	bombard atom.	
SPECIFICATIONS	: (As per one set)	
Number of wave p	<u> </u>	≥5
Currency measure	ment	0.1nA~10μA
Accelerating volta	ge	DC 0~15V
	ge  Stickling Allin Sire United States and the state of t	

ITEM:	A-CLASS	ULTRASONIC
	SOUND	LABORATORY
	APPARATUS	
PART NUMBER:	0201100202	
RASIC FUNCTION:	•	

The ultrasonic wave means that the sound wave of which frequency is higher than the upper limit of hearing of ears. The ultrasonic technique is the modern acoustic one that is used widely. The ultrasonic detection is an important means by which the equipment quality can be guaranteed. The ultra-B instrument has become a favorable helper for human healthy. The ultrasonic inspection is one of main methods by which the non-destructive test is carried out. On base of the propagation rule of ultrasonic wave in media, the material proper and size, shape and distribution of imperfection (crack, inclusion and lack of fusion) on surface of it as well as material properties can be inspected nondestructively by the ultrasonic wave under conditions of the influence of material proper of detected work pieces or acoustic property of internal defect upon the ultrasonic wave propagation. The ultrasonic inspection can detect the heavy forging due to higher sensitivity and stronger penetrability. The detected material is up to much more meter in thickness and the material can be detected on one side so that the on-line inspection and monitoring can be implemented. This apparatus is a nondestructive ultrasonic pulse reflection-type detecting instrument. It is not only used for medicine as ultrasonic diagnostic apparatus but also is used for industry as ultrasonic detector. This apparatus is not only used for the medical physical experiment in medical specialty but also is used for the fundamental physical, modern physical and comprehensive designed experiments in common universities and colleges and technical secondary schools due to the rich, safe and reliable experimentation as well as extensive application.

The following experiments can be carried out when this apparatus is used:

- 1. Use A-class ultrasonic laboratory apparatus to measure the sound velocity in water and thickness of water layer;
- 2. Use A-class ultrasonic laboratory apparatus to measure the thickness of viscera of human body;
- 3. Use A-class ultrasonic laboratory apparatus to measure the width of human brain;
- 4. Use A-class ultrasonic laboratory apparatus to measure the thickness of solid and to carry out the ultrasonic nondestructive inspection.

## SPECIFICATIONS: (As per one set)

\ 1 /	
Pulsed voltage:	450V
Amplification gain:	>50dB
Triggering mode:	Synchronous triggering

& EQUIRMENT.

Output amplitude limiting:	8V
Ultrasonic sound probe:	Integrative send receive, double channel Frequency: 2.5
	MHz

CHILLA ELLI CATIONAL DESTRUMENT & EQUIDANENT CORP.

ITEM:	HOLOGRAPHY EXPERIMENT	
	SERIES	
PART NUMBER: 0201100500		<b>a</b>
BASIC FUNCTION:		15 0 5 Sec.
With this set of components, students can make		1 1 1
	ogram, plane image hologram, one step	
	ogram and two step rainbow hologram.	
SPECIFICATIO	ONS: (As per one set)	
Table Top		GSZ2 type, 1.2×0.8m or 1.5×1.0m
Table Suppo	ort	1.2m or 1.5m
He-Ne Laser	•	5mW
Exposure Ti	mer	0.1~99s
White Black	Film	ISO100/21°
Lamp		100W
Beam Splitte	er	7:3,φ36mm
Beam Splitte	er	5:5,70×50mm

ITEM:	LABORATORY APPARA	TUS FOR OPTICAL
	FIBER TRANSMISSIO	N WITH SOUND
	SIGNAL	
PART NUMBER:	0201100601	

The optical fiber is a wave-guide used to guide the light wave and is a new transmission media. The light wave is used as the carrier wave of optical fiber communication that is a contact method when the optical fiber is used as the transmission media. The research effort to optical fiber used as the transmission media of light is a hard course. After the Doctor Gao Kun, the Chinese of British Nationality published a paper possessed of the historical significance in 1966, in which the possibility of realization for low-loss transmission information with optical fiber was illuminated theoretically, the development effort to optical fiber was started expeditiously. After 1970 when is reputed as the first year of optical fiber communication, the optical fiber system is developed onto the practical stage with the development of optical fiber communication technique.

With the development of optical fiber communication and optical fiber sensing techniques, the optical fiber technique is promoted to applying in many fields. The optical fiber communication technique that the optical fiber used as the information transmission media not only is an important symbol of new technical revolution but also is a main transmission means in network of future information society.

The students are able to know that how to modulate, transmit and demodulate the light wave through the test for optical fiber transmission with sound signal so that we have had an acquaintance with optical fiber communication primarily. We can know the optical fiber transmission system structure through experimentation and be familiar with the testing method for basic property and main features of semiconductor electrolight/photoelectricity devices as well as have an acquaintance with the commissioning technique of optical fiber transmission system with sound signal.

The following experiments can be carried out when this apparatus is used:

- 1. Measurement for electro light features of LD transmitted optical fiber components;
- 2. Measurement for features and responsibility of silicon photoelectric diode (SPD);
- 3. Measurement for relationship between LD bais current and maximum modulated amplitude of non-discontinued distortion.
- 4. Measurement for amplitude-frequency features of modulation and amplification circuit of optical signal transmitter;
- 5. Optical signal reception experimentation;
- 6. Amplification of optical signal and transmission of speech signal;

SPECIFICATIONS: (AS PER ONE SET)



Sound signal generator:	Measuring range: 50Hz-20KHz
Output amplitude of signal generator:	0-2V
Working current of LD laser diode:	<25mA

CHILLA ELLI CALLO WALL THE FREIGHT & ELD LITE MENT CORR.

ITEM:	PULSED NUCLEAR RESONANCE APPARATUS	MAGNETIC	
PART NUMBER:	0201100701		
BASIC FUNCTION:			
<ol> <li>FID can be observed, the apparent spin-spin relaxation time can be estimated, and the influence of homogeneity of magnetic field upon the resonance signal can be realized;</li> <li>The spin echo signal can be observed and the spin-spin relaxation time of sample can be measured;</li> <li>The spin-lattice relaxation time of sample can be measured by the reverse recovery method.</li> <li>The chemical shift of dimethyl benzene sample can be measured.</li> </ol>		A CONTRACT OF THE PARTY OF THE	
SPECIFICATIONS: (A	as per one set)		
Resonance frequency:	Resonance frequency:		20MHz
Pulse power:	Pulse power:		0.3W
Switching amplifier gain	Switching amplifier gain:		≥20dB
Phase-locked amplifier gain:		≥40dB	
Uniformity of magnetic field after the shimming plate is added:		≤3ppm	
power supply (continuous adjustable)		0-6.00V	
magnet gap		20mm	
Corresponding magnetic field		0.47T	
orking temperature		36.50°C	

ITEM:	FARADAY EI	FARADAY EFFECT & ZEEMAN	
	EFFECT	INTEGRATED	
	EXPERIMEN	TAL APPARATUS	
PART NUMBER:	0201100803		

In 1945, Faraday found a phenomenon when searching for relationship between electromagnet phenomenon and optical phenomenon. When a plane polarized light beam passes through a media, and if magnetic field is imposed in the direction of the light beam, the plane of polarization of the light rotates for an angle, which means the magnetic field makes the media having the optical rotation. This is now called Faraday Effect. In 1896, P.Zeeman, the Holland physical scientist found that when light source is put in sufficiently strong magnetic field, its original spectral line will split into several ones. The split spectral lines are polarized, and number of split spectral lines varies along with variation of energy level. This phenomenon is now called Zeeman Effect. Faraday and Zeeman Effect is one of the most important achievements of 19 century. It strongly supports the electromagnetic theory of light.

Faraday-Zeeman effect integrated experimental apparatus is a new generation that bases on old type. Original 1-dimensional adjustable He-ne laser is replaced by 2-dimensional adjustable semiconductor laser, which makes the adjustment more accurate and the output power of laser is more stable. The central magnetic limit of the electromagnet is also greatly increased. It can reach 1.4T. Angle measuring vernier is replaced with screw micrometer (which transfers angular displacement to linear one). The apparatus can be used for optical and contemporary physics experiment in universities and colleges and it can also be used for study of material characteristics, light spectrum and magneto-optic effect.



Semiconductor laser:	wavelength 650nm power>1.5mW light spot diameter 1mm	
Electric magnet:	magnetic limit 1.35T(is related to excitation source)	
Excitation source:	max output power 5A Max output voltage 30V	
L-voltage mercury lamp	ignition voltage 1500V tube diameter 6.5mm	
Standard light aperture	40mm distance 2mm	
Reading microscope:	resolution 0.01mm measuring range 8mm	
Faraday Effect	min angle measurement 2 minutes	

ITEM:	SURFACE MAGNETO-OPTIC KERF	
	EFFECT EXPERIMENTAL SYSTEM	
PART NUMBER:	0201100902	
BASIC FUNCTION	N:	]
The performance an	nd experimental stability of the system are al	
greatly improved.		
First, the metal pl	ate experimental platform is replaced with	1
black-anodic oxidiz	ed duralumin, so that the removability and	1
optical property of	the platform is extensively increased. Al	With Mills
optical components	are fixed to the platform with M6 screws	,
which greatly facilita	ates the experimental operation.	AR
Secondly, the test of	quality level of the apparatus is doubled, so	
stability in the large	of final test signal is greatly improved, which	
enables the further	study of properties of magnetic thin film o	f
monatomic layer. T	he apparatus plays an important role in the	
study of magnetic o	order, magnetic anisotropy, interlayer coupling	P
and phase transition of magnetic ultrathin film.		
Thirdly, the ring electromagnet is further improved. The size of the		e gr
magnet is reduced	while the central magnetic limit is kep	t
unchanged, which	facilitates application of extreme vacuum	1
system to enable in	-site measurement of magnetic thin film and	1
ultrathin film.		
SPECIFICATIONS	S: (As per one set)	
Packed type vibratio	on reduction platform:	Table top size: 1200×900mm; bolt hole: M
		pitch: 25×25mm
High stability semiconductor laser:		wavelength 650nm
		Output power 2mW; min light spot diame
	Cr	1 mm
Polarizing prism:		clear aperture:8mm
	***	Extinction ratio: 10-5; transmittance:90Ċ
Ring electromagnet:	71.	central magnetic limit:2800Gs; gap:40mm
Precise constant curi	rent source:	Peak voltage: 3
		1

Max output current: 10A

ITEM:	MICROWAVE-BAND	ELECTRON SPI	N
	RESONANCE	LABORATOR	Y
	APPARATUS		
PART NUMBER:	0201101000		
	<b> </b>		

Electron spin resonance is named as the electron paramagnetic resonance also, which means that when the electron spin magnetic moment is affected by the electromagnetic wave of response frequency in magnetic field, the resonant transition phenomenon is to occur among the magnetic energy levels of them. This phenomenon can be observed in the paramagnetic substance (i.e. contained uncoupled electronic chemical compound) possessed of uncoupled spin magnetic moment, so the electron paramagnetic resonance is used to detect the uncoupled electron in substance and the mutual effect between electron and atom, with the result that this is an important method by which the microstructure information of related substance can be achieved. This electron paramagnetic resonance is possessed of higher sensitivity and resolution, which is able to go deep into the substance carrying out the fine analysis meanwhile the sample is not destructed and it is not interfered with the chemical reaction. At present, this technique is being applied widely in the following fields such as physics, chemistry, biology, medicine and life sciences.

This microwave-band electron spin resonance laboratory apparatus has been improved on the basis of originality. The microwave frequency counter not only is added to measure the microwave source frequency but also the digital Gauss meter is added to measure the resonant magnetic field accurately besides. Additionally, the exciting current is shown on digital gauge so that the magnetic field can be adjusted easily. This apparatus is possessed of the following features such as easy adjustment, reliable data and rich testing content, which is able to use for the modern physical experimentation and professional researching experimentation.

The following experiments can be carried out when this apparatus is used:

- 1. Observe the electron spin resonance phenomenon of standard sample DPPH.
- 2. Use the microwave frequency counter to measure the operating frequency during experimentation and estimate the required stationary magnetic field according to the resonance conditions.
- 3. Use the Gauss meter to measure the stationary magnetic field and calculate factor g of sample DPPH according to the resonance conditions.
- 4. Adjust the sample lumen in length, measure position at three resonance points and calculate the wavelength of wave-guide.



Short circuiting piston:	measuring range: 0~65mm	
Outside diameter of sample tube:	4.8mm	
Microwave frequency counter:	measuring range:	
	8.2GHz-12.4GHz, resolution: 0.005GHz	
Digital Gauss meter:	measuring range: 0~2T, resolution: 0.0001T	
Wave guide specification:	BJ-100 (inside dimension of wave guide:	
22.86mm×10.16mm)		

CHIMA EDUCATIONAL DESTRUMENT & EDUTAMENT CORP.

ITEM:	CURIE	TEMPERATURE
	MEASUREMENT	LABORATORY
	APPARATUS OF	FERROMAGNETIC
	MATERIAL (COMPL	UTER ACQUISITION)
PART NUMBER:	0201101100	
D A GLG EVINGERON	•	

The magnetic material is used widely in the following fields such as electric power, communication, electronic instrument, and automobile and computer as well as information storage. In recent years, it is the nonreplaceable material that the high and new-technology industries are being promoted to developing and the contemporary civilization is making progress. It is very important to research the basic property of magnetic material during physical experimentation. The Curie temperature is the physical quantity used to characterize the basic property of magnetic material, which reflects the transformation temperature of magnetic material from ferromagnetism to paramagnetism.

The bridge method is used to measure the temperature of ferromagnetic material when the spontaneous magnetization of it disappears according to the property that the magnetic moment of ferromagnetic material is to change with the changing temperature. The platinum resistance temperature sensor is used to record the temperature; the digital voltmeter is used to take a reading of voltage and then draw up the T~V curve on which the Curie temperature TC is determined. The basic property of this magnetic material can be comprehended deeply through measurement for the Curie temperature of soft magnetic ferrite. Computer can acquire the data and measure out the temperature voltage curve automatically so that the automatic operation combines with the manual operation, i.e. the manual operational ability of students not only can be improved but also an ability by which this classical experimentation is possible to carry out is trained during measurement. This apparatus is possessed of the following features such as firm system structure, steady and reliable property, which is suitable for the modern physical experimentation as well as researching and designing experimentation in universities and colleges.



Signal generator	Frequency modulation 500Hz-1500Hz
	Amplitude modulation 2V-10V (peak-peak value)
Digital frequency meter	Resolution 1Hz
	Measuring range 0-9999Hz
AC voltmeter	Resolution 0.001V
	Measuring range 0-1.999V
Digital thermometer	Measuring range 0°C-150°C
	Resolution 1°C
Ferromagnetic sample	Curie temperature 50 °C $\pm 2$ °C and 90 °C $\pm 2$ °C ,
	respectively

CHIMA EDUCATIONAL DESTRUMENT & EDUTAMENT CORP.

ITEM:	HUGE MAGNETORESISTANCE	EFFECT
	LABORATORY APPARATUS	
PART NUMBER:	0201101300	
DACIC ELINGTION	·	

Generally speaking, the magnetic metal and alloy are possessed of the magneto resistance phenomenon. The magneto resistance is a phenomenon that the resistance changes in a certain magnetic field. The huge magneto resistance is a phenomenon that the resistance reduces suddenly in a certain magnetic field. The reductive amplitude is more than magneto resistance value of magnetic metal and alloy material 10 times above. The huge magneto resistance effect is applied extensively to the high-density magnetic reading heads and magnetic store elements. It is often used to measure the displacement and angle also. Compared with the photoelectric sensor, the huge magneto resistance sensor is possessed of the following features such as higher sensitivity, lower power consumption, excellent reliability and compact in volume as well as service under the atrocious conditions.

This apparatus is used as the new-type huge magneto resistance sensor so that the students can know the principle and application of the huge magneto resistance effect. It is used for the fundamental physical, modern physical and comprehensive designed experiments in common universities and colleges and technical secondary schools due to the simple operation, rich, safe and reliable experimentation.

The following experiments can be carried out when this apparatus is used:

- 1. Know the huge magneto resistance effect principle and study the calibration method of huge magneto resistance sensor. Use the huge Magneto resistance sensor to measure the weak magnetic field;
- 2. Determine the relationship between included angle of sensitive axis on huge magneto resistance sensor to measured magnetic field and sensitivity of sensor;
- 3. Determine the relationship between sensitivity of huge magneto resistance sensor and operating voltage;
- Use the huge magneto resistance sensor to measure the current of electrified wire.



Huge magnetoresistance sensor:	Linearity range: 1.5Gs-10.5Gs
	Saturated magnetic field: 15Gs
	Sensitivity: 3.0mV/V·Gs-4.2 mV/V·Gs
Sensor power:	1.5V~12V continuous adjustable
Helmholtz coils:	Turn number of single coil: N=200,
	10cm in semi-diameter
Constant current for Helmholtz coils:	Output current: 0~0.8A continuous
	adjustable
Measured direct current:	Output current: 0~5A continuous adjustable

CHIRA RITUCATIONAL DESTRUMENT & FOUR PARTY CORP.

ITEM: OPTICAL EXPERIMENT SYSTEM	OPTICAL EXPERIMENT SYSTEM	
PART NUMBER: 0201200000		
BASIC FUNCTION:		
For a better understanding of the false color		
photography, this device and a brief introduction to	0.0	
Color Composites is given for more advanced students.		
As it involves many fundamental knowledge of color		
coding, decoding, memory, reconstruction, chroma,	(8) and (1) an	
image process, etc., students should be able to explain	200	
how colors is " preserved " and many other related		
techniques.		
SPECIFICATIONS: (As per one set)	3.	
White Light Source	30W	
Diameter of Holes	0.1mm-2mm	
Optical Rail	2m	
Lens	f=70,190mm	
CHINARIDICATIONALINGUAL		

ITE	M:	LASER	RAMAN	N
		SPECTROMETER	141111111	
PAR	T NUMBER:	0201400200		
	IC FUNCTION:	<u> </u>		
		opy is a useful instrume	nt for the	
identification of a wide range of substances in physics and				
chemistry laboratories of scientific research institutes,				
universities and colleges. It is a straightforward,				
non-destructive technique requiring no sample preparation,				
and i	t involves illuminat	ing a sample with mono	ochromatic	
light	and using a spectro	meter to examine the lig	ght scattered	
by a	sample.			
Features:				
•	Computer-controlled, user friendly interface, capable of		f	
automatic record of Raman spectra.				
Monochromatic system with high resolution and low				
stray light.				
Single-photon solid state lase used as light source.				
• External optic path system provided, with good stability		y		
and high accuracy.				
•	Various accessories available for analysis of liquid and			
I	solid samples.		_<	<
•	Trap filter available	e for cutting stray light.	R	_
SPE	CIFICATIONS: (A	AS PER ONE SET)	15	
Mon	ochromator	A		
Opti	cal Grating		<b>Y</b>	
Slit '	Width	10		
Note	ch Filter (optional	)		
Wav	elength	(C)		
Sing	le-photon Counte	r		
Integ	gration Time	7		
Max	Count	Y		
Wavelength Range				
Wavelength Accuracy				
Wav	Wavelength Repeatability			
	Stray Light			

≤0.2nm at 586nm

Half-width of Spectral Line